Notice of References Cited Application/Control No. 10/614,921 Examiner Cristina Owen Sherr Applicant(s)/Patent Under Reexamination HATAKEYAMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2001/0018736	08-2001	Hashimoto et al.	713/1
	В	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G.	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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